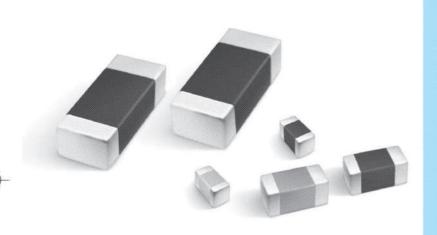
# **Multi Layer Ceramic Capacitors**



SMD Type	5
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# **Multi Layer Ceramic Capacitors**

### Introduction

SAMWHA's series of multilayer ceramic(MLC) chip capacitors is designed to meet a wide variety of need. Multilayer ceramic chip capacitors are available in both class I and class II formulations. Temperature compensation formulations are class I and temperature stable and general application formulations are classified at class II. The class I multilayer ceramic capacitors are COG with negligible dependence of electrical properties on temperature, voltage, frequency. The most of commonly used class II dielectric are X7R, X5R and Y5V. The X7R provides intermediate capacitance values which vary  $\pm 15\%$  over the temperature range of -55°C to 125°C. The X5R provides intermediate capacitance values which vary ±15% over the temperature range of -55°C to 85°C. The Y5V provides the highest capacitance value which vary from 22% to -82% over the temperature range of -30°C to 85°C. All class II capacitors vary in capacitance value under the influence of temperature, operating voltage and frequency. We offer a complete line of products for both class I and II.

### **Features**

- · Samwha's high density ceramic bodies offer superior performance and reliability
- Samwha offer various temperature characteristics, rated voltage and packing method
- · Material with high dielectric constant and superior manufacturing technology allows very high values in a small size
- · Solder coated terminals offer superior solderability

## **Applications**

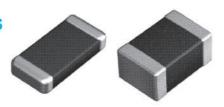
Wide applications throughout commercial and industrial market.

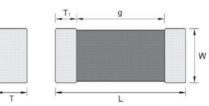
- Communication products like Cellular Phone, Pager, Codeless phone
- Multimedia products like DVD, CD-ROM, FDD, HDD, Game machine, Computer, Note book, Digital camera, LCD
- Audio visual products like TV, Camcorder, Minidisk, MP3 Player
- Communication products like Electronic tuner, Duplexer, VCXO, TCXO, Modem
- OA equipment products like Printer, Copy Machine, Fax Machine
- \* special specification like a Automobile, Medical, Military, Aviation should be discuss with our sales representatives

# **SMD Type**

# **SMD Type**

# **Shape & Dimensions**



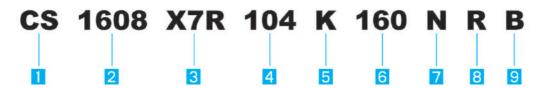


(Unit:mm)

			Dimensions		
Code(inch)	Le	Length		dth	T1(min)
	L	Tol(±)	W	Tol(±)	(,
0603(0201)	0.60	0.03	0.30	0.03	0.05
1005(0402)	1.00	0.05	0.50	0.05	0.05
1608(0603)	1.60	0.15	0.80	0.10	0.10
2012(0805)	2.00	0.20	1.25	0.15	0.10
3216(1206)	3.20	0.30	1.60	0.20	0.15
3225(1210)	3.20	0.40	2.50	0.25	0.15
4520(1808)	4.50	0.40	2.00	0.25	0.20
4532(1812)	4.50	0.40	3.20	0.30	0.20
5750(2220)	5.70	0.50	5.00	0.40	0.30

<sup>\*1608</sup> Size  $\geq$  10 $\mu$ F  $\Rightarrow$  W : 0.8 $\pm$ 0.15, T : 0.8 $\pm$ 0.15

# **How to Order**(Product Identification)



### Type

#### 2 Size Code

CS: SMD

This is expressed in tens of a millimeter.

SA: ARRAY

The first two digits are the length, the last two digits are width.

The second second second		Anna and annual and a state of the state of							
Size(mm)	0603	1005	1608	2012	3216	3225	4520	4532	5750

### Temperature Coefficient Code

Temperature Characteristice	Temperature Range	Capacitance Change or Temperature Coefficient	Operating Temperature Range
C0G	-55 to 125°C	0±30ppm/℃	-55 to 125°C
X7R	-55 to 125°C	±15%	-55 to 125°C
X5R	-55 to 85°C	±15%	-55 to 85°C
Y5V	-30 to 85°C	+22, -82%	-30 to 85°C

The nominal capacitance value in pF is expressed by three digit numbers.

The first two digits represents significant figures and the last digit denotes the number of zero

Ex.) 104 = 100000pF R denotes decimal 8R2 = 8.2pF

### 5 Capacitance Tolerance Code

Code	Tolerance	Code	Tolerance
В	±0.1pF	М	±20%
С	±0.25pF	Р	+100, -0%
D	±0.5pF	Z	+80, -20%
F	±1.0%	Н	+0.25/-0pF
G	±2.0%	I	+0/-0.25pF
J	±5%	U	+5/-0%
K	±10%	٧	+0/-5%

### 6 Voltage Code

Code	6R3	100	160	250	500	101	201	251	631	302
Vol.	DC 6.3V	DC 10V	DC 16V	DC 25V	DC 50V	DC 100V	DC 200V	DC 250V	DC 630V	DC 3000V

#### 7 Termination Code

Ex.) N: Ni-Sn(Nickel-Tin Plate)

### 8 Packing Code

Ex.) R: Reel Type B: Bulk Type

### 9 Thickness Option

C:/\	Thicknes	Thickness(mm)		Code Size(mm)	Thickne	ess(mm)	Carla
Size(mm)	t	Tol(±)	Code	Size(mm)	1	Tol(±)	Code
0603/1005	0.3	0.03		3216	1.15	0.15	Е
1005	0.5	0.05		3216/3225	1.6	0.2	- 1
2012	0.6	0.1	Α	3225	1.8	0.2	J
1608	0.8	0.1	В	3225/4532/5750	2	0.25	K
2012/3216	0.85	0.15	В	3225/4532/5750	2.5	0.25	L
2012	1.25	0.15	Е				

Size(mm)	Code	Packaging	Size(mm)	Code	Packaging
0603/1005	-	Paper Taping	3216	E	Embossed Taping
1005	-	Paper Taping	3216/3225	1	Embossed Taping
2012	Α	Paper Taping	3225	J	<b>Embossed Taping</b>
1608	В	Paper Taping	3225/4532/5750	K	Embossed Taping
2012/3216	В	Paper Taping	3225/4532/5750	L	<b>Embossed Taping</b>
2012	Е	Embossed Taping			

# **SMD Type**

# **Typical Performance Characteristics**

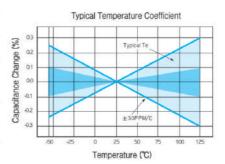
## COG

### Application

Suited for precision circuits, requiring stable dielectric characteristics, negligible dependence of capacitance and dissipation factor on time, voltage and frequency.

### **Dielectric Characteristics**

Temperature Characteristic	0±30ppm/℃
Operating Temperature	-55~125℃
Capacitance Tolerance	>10pF: $\pm$ 5%, $\pm$ 10%,( $\pm$ 1%, $\pm$ 2%, $\pm$ 20%) $\leq$ 10pF: $\pm$ 0.1pF, $\pm$ 0.25pF, $\pm$ 0.5pF
Dissipation Factor & Q	≥30pF: DF≤0.1%, Q≥1000 <30pF: Q≥400+20×C
Insulation Resistance	More than 10,000MΩ or 500ΩF (Whichever is smaller)
Dielectric Strength	>3×RVDC
Test Voltage	0.5 to 5Vrms(≤1000pF), 1±0.2Vrms(>1000pF)
Test Frequency	$1\pm0.1$ MHz( $\leq$ 1000pF), $1\pm0.1$ kHz( $>$ 1000pF)



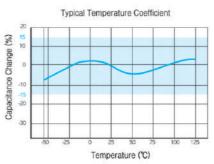
# X7R

### **Application**

Stable class || dielectric properties, suited for by-pass and coupling purposes, filtering, frequency discrimination, DC blockage, and as voltage transient suppression elements.

### **Dielectric Characteristics**

Temperature Characteristic	±15%
Operating Temperature	−55~125°C
Capacitance Tolerance	±10%, ±20%,(±5%, +80~-20%)
Dissipation Factor & Q	50V Min.: 2.5% Max. 25V Min.: 3.0% Max. 16V Min.: 3.5% Max. 10V Min.: 5.0% Max. 6.3V Min.: 5.0% Max. Thin layer lange capacitors type 12.5% Max.
Insulation Resistance	More than $10,000M\Omega$ or $500\Omega$ F(Whichever is smaller) Thin layer lange capacitors type $50\Omega$ F Min.
Dielectric Strength	>2.5×RVDC
Test Voltage	1±0.2Vrms(≤10μF) 0.5±0.1Vrms(>10μF)
Test Frequency	1±0.1kHz(≤10μF) 120±24Hz(>10μF)



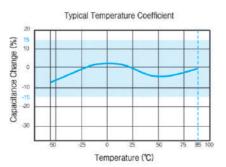
# X5R

### **Application**

Stable class || dielectric properties, suited for by-pass and coupling purposes, filtering, frequency discrimination, DC blockage, and as voltage transient suppression elements.

### **Dielectric Characteristics**

Temperature Characteristic	±15%
Operating Temperature	-55~85°C
Capacitance Tolerance	±10%, ±20%,(±5%, +80~-20%)
Dissipation Factor & Q	50V Min.: 2.5% Max. 25V Min.: 3.0% Max. 16V Min.: 3.5% Max. 10V Min.: 5.0% Max. 6.3V Min.: 5.0% Max. Thin layer lange capacitors type 12.5% Max.
Insulation Resistance	More than 10,000M $\Omega$ or 500 $\Omega$ F (Whichever is smaller) Thin layer lange capacitors type 50 $\Omega$ F Min.
Dielectric Strength	>2.5×RVDC
Test Voltage	1±0.2Vrms(≤10 $\mu$ F) 0.5±0.1Vrms(>10 $\mu$ F)
Test Frequency	$1\pm0.1$ kHz( $\leq 10\mu$ F) $120\pm24$ Hz( $>10\mu$ F)



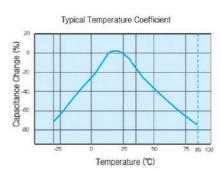
## Y5V

### Application

The Hi-K(Y5V) dielectrics deliver high capacitance density and are ideally suited for applications where space is at a premium, or as replacement for tantalum capacitors. Typically applications include use as by-pass or decoupling elements. Best performance is obtained at or near room temperature, with low DC bias.

#### **Dielectric Characteristics**

Temperature Characteristic	+22%~-82%
Operating Temperature	-30~85°C
Capacitance Tolerance	-20~+80%(±20%)
Dissipation Factor & Q	50V Min.: 5% Max. 25V Min.: 7% Max. 16V Min.: 9% Max. 10V Min.: 12.5% Max. 6.3V Min.: 15% Max. Thin layer lange capacitors type 20% Max.
Insulation Resistance	More than $10,000M\Omega$ or $500\Omega$ F(Whichever is smaller) Thin layer lange capacitors type $50\Omega$ F Min.
Dielectric Strength	>2.5×RVDC
Test Voltage	1±0.2Vrms(≤10 $\mu$ F) 0.5±0.1Vrms(>10 $\mu$ F)
Test Frequency	$1\pm0.1$ k Hz( $\leq10\mu$ F) $120\pm24$ Hz( $>10\mu$ F)



# **SMD Type**

# Appendix |

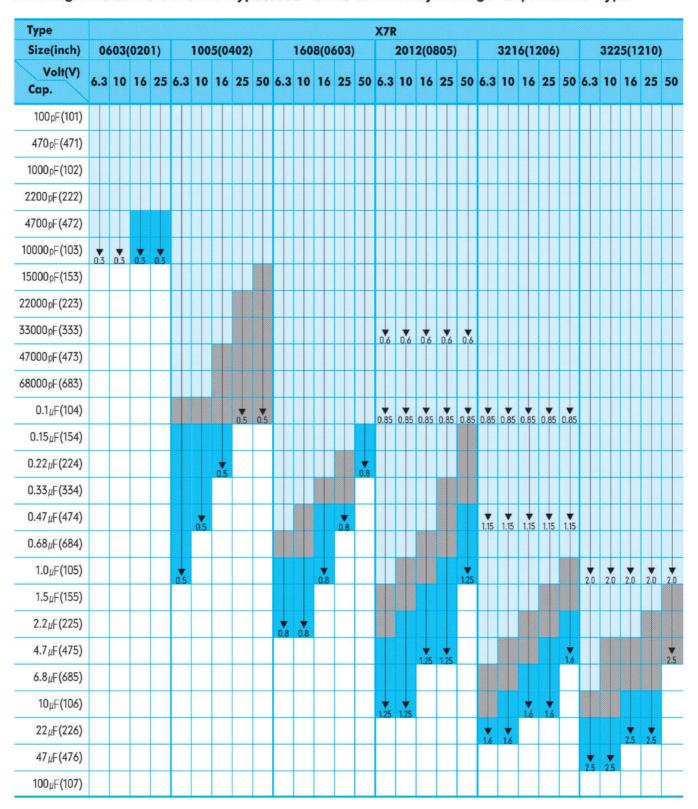
COG-Temperature Compensating Type(0603~3216)

Type Size(inch)	0603	(0201)	100	5(0402)	C0 1608	(0603)	2012	(0805)	3216(	1206)
Volt(V) Cap.	25	50	25	50	25	50	25	50	25	50
0.5pF(0R5)										
1 <sub>p</sub> F(010)										
2pF(020)										
3pF(030)										
4pF(040)										
5pF(050)										
6pF(060)										
7 <sub>p</sub> F(070)										
8pF(080)										
9pF(090)					100 =					
10pF(100)										
12pF(120)										
15pF(150)										
18pF(180)										
22pF(220)										
27pF(270)										
33pF(330)										
39pF(390)										
47 pF (470)										
56pF(560)										
68pF(680)										
82pF(820)										
100 <sub>p</sub> F(101)										
120 <sub>p</sub> F(121)										
150 <sub>p</sub> F (151)										
180 <sub>p</sub> F(181)										
220pF(221)		0.3								
270pF(271)		1								
330pF(331)										
390pF(391)										
470pF(471)										
560pF(561)										
680 <sub>p</sub> F(681)										
820pF(821)										
1000pF(102)	0.3									
1200 <sub>p</sub> F(122)									+	<b>+</b>
1500pF(152) 1800pF(182)									1.15	1.15
2200pF(182)							▼.	<b>.</b>		
							0.6	0.6		
2700 <sub>p</sub> F(272) 3300 <sub>p</sub> F(332)										
5900pF(332)										
1700pF(472)										
5600pF(562)										
5800pF(582)										
3200 pF (822)				0.5						
0000pF(103)			0.5	0.5	0.8	0.8				
2000pF (123)			0.3		0.0	0.0				
5000pF (153)										
8000pF (183)										
2000pF(223)										
7000pF(273)										
3000pF(333)							1.25	1.25		
7000pF(473)							1.23	1.23		
6000pF(563)										
3000pF(683)										
2000pF(823)										
0.1 <sub>µ</sub> F(104)									1,60	1,60

Temperature Compensating Type : Dissipation Factor Page 22 (No.5)

# Appendix ||

X7R-High Dielectric Constant Type(0603~3225) & Thin Layer Large-Capacitance Type



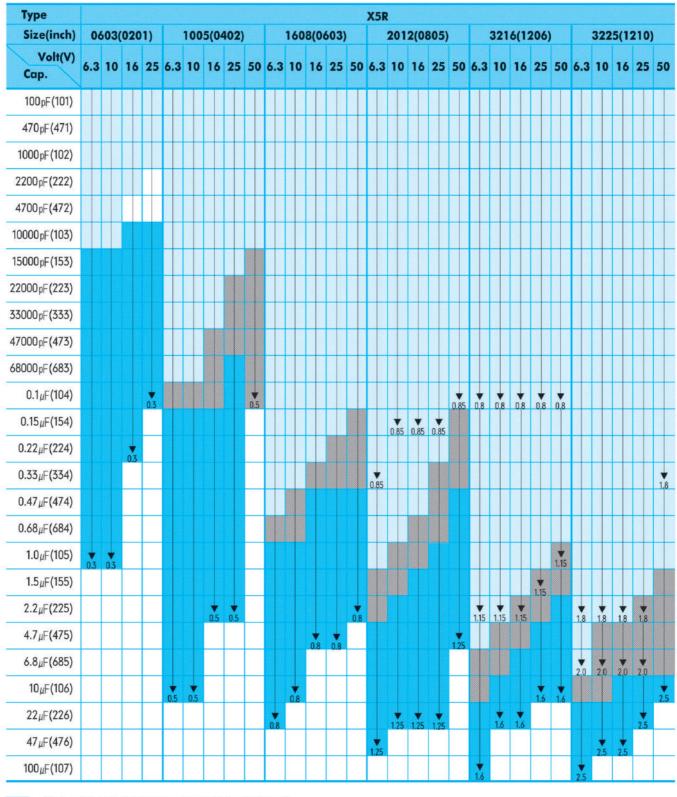
General Type: Dissipation Factor Page 22(No.5)

\*General Type : Dissipation Factor Page 22(No.5)

Thin Layer Large-Capacitance Type: Dissipation Factor Page 22(No.5)

# **SMD Type**

### X5R-High Dielectric Constant Type(0603~3225) & Thin Layer Large-Capacitance Type



General Type: Dissipation Factor Page 22(No.5)

\*General Type : Dissipation Factor Page 22(No.5)

Thin Layer Large-Capacitance Type: Dissipation Factor Page 22(No.5)

### Y5V-High Dielectric Constant Type(0603~3225) & Thin Layer Large-Capacitance Type

Туре													Y5V												
Size(inch)		100	5(04	102)			160	08(0	503)			201	2(08	305)			321	6(12	206)			322	25(1:	210)	
Volt(V)	6.3	10	16	25	50	6.3	10	16	25	50	6.3	10	16	25	50	6.3	10	16	25	50	6.3	10	16	25	50
1000pF(102)																									
2200pF(222)																									
4700 <sub>p</sub> F(472)																									
10000pF(103)																									
15000pF(153)																									
22000pF(223)					0.5																				
33000 <sub>p</sub> F(333)					0.3																				
47000pF(473)																									
68000pF(683)																									
0.1 <sub>μ</sub> F(104)				0.5																					
0.15 <sub>μ</sub> F(154)				0.5																					
0.22μF(224)										0.8															
0.33 <sub>μ</sub> F(334)										U.0															
0.47µF(474)			0.5						0.8																
0.68 <sub>µ</sub> F(684)			0.5						U.0																
1.0 <sub>μ</sub> F(105)	0.5	0.5													1.25				1.15	1.15					
1.5 <sub>μ</sub> F(155)	0.5	0.5													1.23				1.13	1.13					
2.2 <sub>µ</sub> F(225)								•								1.15	1.15	1.15							
3.3 <sub>μ</sub> F(335)							•	0.8								1,15	1,15	1.15				<b>V</b>	1,8	<b>V</b>	*
4.7 <sub>μ</sub> F(475)						0.8	0.8						¥	1.25							1,8	1.8	1.8	1.8	1.0
6.8μF(685)						0.8							1.25	1.25							1.8				2,0
10μF(106)											1.25	1.25									2.0	*		2.0	2.5
22µF(226)											1.25	1.25									2.0	2.0	2.0	2.0	2.5
47μF(476)					-																		2.0		
100μF(107)																1.6	1.6	1.6	1.6	1.6	2.5	2.5			

General Type: Dissipation Factor Page 22(No.5)

\*General Type : Dissipation Factor Page 22(No.5)

Thin Layer Large-Capacitance Type: Dissipation Factor Page 22(No.5)

# **SMD Type-High Voltage**

# **SMD** Type-High Voltage

### **Product Offering**

SAMWHA high voltage MLCC products with the temperature characteristics of C0G and X7R are designed for commercial and industrial applications. The products are applied to DC-DC converters and ballast circuit to reduce ripple noise and diverting potentially unsafe transients in various sizes with working voltage up to DC 7kV. These high voltage capacitors feature a special internal electrode design which has capacitor network to reduce voltage concentrations by distributing voltage throughout the entire capacitor.

### **Features**

- High reliability
- The highest voltage rating by the special internal electrode design
- Wide voltage level: from 100V<sub>DC</sub> to 7,000V<sub>DC</sub>
- · Surface mount suited for wave and reflow soldering
- RoHS compliant

# **Applications**

- DC-DC Converters
- Network Equipments
- Back-Lighting Inverter
- Lighting Ballast
- Modem & Power Supply
- LAN/WLAN Interface
- \* special specification like a Automobile, Medical, Military, Aviation should be discuss with our sales representatives

### **Special Options for the Safety**

- Inset electrode margins to prevent short mode failure resulted from the crack by mechanical bending
- Soft termination is optionally available to reduce possibility for the crack of MLCCs by mechanical bending stress

# CS 4532 X7R 471 K 302 N R K

1 Type

2 Size Code

CS: SMD

Size(mm) 1608 2012 3216 3225 4520 4532 5750 7566 9595

Dielectric (Temp. Coefficient) 4 Capacitance

1st two digits are value, 3rd digit denotes number of zeros; 331 = 330pF, 104 = 100000pF, 8R2 = 8.2pF

COG, X7R

5 Tolerance

Code	Tolerance	Code	Tolerance
В	±0.1pF	С	±0.25pF
D	±0.50pF	F	±1%
G	±2%	J	±5%
K	±10%	М	±20%
Z	+80~-20%		

6 Rated Voltage Code

1st two digits are value, 3rd digit denotes number of zeros; 302 = 3,000V, 502 = 5,000V, 722 = 7,200V

7 Plating

8 Packing

Ni / Sn Plated

B: Bulk Pack R: Reel Pack C: Case Box

### Thickness Option

Si/\	Thicknes	s(mm)	Carda	S:/	Thickne	ess(mm)	Codo
Size(mm)	t	Tol(±)	Code	Size(mm)	t	Tol(±)	Code
0603/1005	0.3	0.03		3216	1.15	0.15	E
1005	0.5	0.05		3216/3225	1.6	0.2	- 1
2012	0.6	0.1	Α	3225	1.8	0.2	J
1608	0.8	0.1	В	3225/4532/5750	2	0.25	K
2012/3216	0.85	0.15	В	3225/4532/5750	2.5	0.25	L
2012	1.25	0.15	Е				

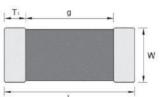
Size(mm)	Code	Packaging	Size(mm)	Code	Packaging
0603/1005	2	Paper Taping	3216	Е	Embossed Taping
1005		Paper Taping	3216/3225	1	Embossed Taping
2012	Α	Paper Taping	3225	J	<b>Embossed Taping</b>
1608	В	Paper Taping	3225/4532/5750	K	Embossed Taping
2012/3216	В	Paper Taping	3225/4532/5750	L	<b>Embossed Taping</b>
2012	Е	Embossed Taping			

# **SMD Type-High Voltage**

# **Shape & Dimensions**







(Unit:mm)

			Dimensions		
Code	Le	ngth	Wi	idth	T1(min)
	L	Tol(±)	W	Tol(±)	• • • • • • • • • • • • • • • • • • • •
1608(0603)	1.60	0.15	0.80	0.10	0.10
2012(0805)	2.00	0.20	1.25	0.15	0.10
3216(1206)	3.20	0.30	1.60	0.20	0.15
3225(1210)	3.20	0.40	2.50	0.25	0.15
4520(1808)	4.50	0.40	2.00	0.25	0.20
4532(1812)	4.50	0.40	3.20	0.30	0.20
5750(2220)	5.70	0.50	5.00	0.40	0.30
7566(3026)	7.50	0.50	6.60	0.50	0.30
9595(3838)	9.50	0.50	9.50	0.50	0.30

<sup>\*1608</sup> Size  $\geq$  10 $\mu$ F  $\Rightarrow$  W: 0.8 $\pm$ 0.15, T: 0.8 $\pm$ 0.15

# **Typical Performance Characteristics**

Dielectric Characteristics	COG(NPO)	X7R
Dielectric Classification	Ultra Stable	Stable
Rated temperature range	–55°C to +125°C	-55°C to +125°C
TCC(Temperature Characteristics Coefficient)	0±30ppm	±15%
Dissifation Factor(tan ∂)	C≥30pF : Q≥1,000 (DF:≤ 0.1%)	2.5% Max.
	$C<30pF: Q \ge 400+20C(DF: \le 1/(400+20C))$	
IR(Insulation Resistance)	500V Below : Rated voltage 2Min 500V Above : 500V 2Min More than 10,000 №	500V Below:Rated voltage 2Min 500V Above:500V 2Min -DC100V~1KV :C≥0.01μF:More than 100MΩμF :C<0.01μF:More than 10,000MΩ -DC2~3KV:More than 6,000 MΩ
Capacitance Tolerance	$(10pF: \pm 0.25pF, \pm 0.5pF$ ≥10pF: ±5%, ±0%	±10%, ±20%
Dielectric strength	630V:150% Rated Voltage 1kV~7.2kV:120% Rated Voltage	100V:150% Rated Voltage 630V:150% Rated Voltage 1kV~7.2kV: 120% Rated Voltage
Aging characteristics	0%	2.5% per decade hr, typical

dache 1p rere 1904.6.3 1:55 AM 페이지16 광진그래픽 CTP-1500\_CMYK-POSI 2400DPI 175LPI T

# Appendix High Voltage Type(100V~3000V)

### **COG-Temperature Compensation Type**

High voltage type

Туре																C	OG															
Size(inch)	1608(	0603)	2012	(0805)		321	6(12	206)			32	25(12	210)				4520	(1808	3)			4	1532	(1812	2)		7066(	3026)		9595(	383	8)
Volt(V) Cap.	100	250	100	250	100	250	630	1000	2000	100	250	630	1000	2000	100	250	630	1000	2000	3000	100	250	630	1000	2000	3000	3000	4000	3000	4000	5000	7000
4.7pF(4R7)																																
5pF(050)																																
7pF(070)																Г																
8pF(080)																																
9pF(090)																																
10pF(100)																																
12pF(120)																																
15pF(150)																																
18pF(180)																																
22pF(220)																																
47 pF (470)																																
56pF(560)																																
68pF(680)																																
82pF(820)																																
100pF(101)																																
180 <sub>p</sub> F(180)																																
220pF(221)																																
330pF(331)									Г																							
470pF(471)																																
560pF(561)																																
680pF(681)																																
1000pF(102)																			Г													
1500pF(152)																																
2200pF(222)								Г																								
2700pF(272)																																
3300pF(332)																																
4700pF(472)																Г																
5600pF(562)																																
6800pF(682)																																
10000pF(103)																																
15000 <sub>p</sub> F(153)					Н																							Н				
22000pF(223)			3													Г																
33000pF(333)		$\exists$			_																							H				

# **SMD Type-High Voltage**

### X7R-High Dielectric Type

High voltage type

Туре													X	7R												
Size(inch)	1608	(0603)	2012	0805)		32	16(12	06)			32	25(12	10)				4520	(1808)					4532(	(1812)		
Volt(V) Cap.	100	250	100	250	100	250	630	1000	2000	100	250	630	1000	2000	100	250	630	1000	2000	3000	100	250	630	1000	2000	3000
220pF(221)																										
330pF(331)																										
470pF(471)																1111										
680pF(681)																										
1000pF(102)																										
1500pF(152)																							011111			
2200pF(222)																										
3300pF(332)																										
4700 <sub>p</sub> F(472)																										
5600pF(562)																										
6800pF(682)																										
10000pF(103)																										
15000pF(153)																										
18000pF(183)																										
22000pF(223)																										
33000pF(333)																				-						
47000pF(473)																										
68000pF(683)																										
0.1 <sub>μ</sub> F(104)																										
0.15μF(154)																										
0.22µF(224)																										
0.33 <sub>µ</sub> F(334)																										
0.47μF(474)																										
0.68µF(684)																										
1.0μF(105)																										
2.2µF(225)																				v e						

Size	Vr(V)	100pF	470pF	1.0nF	2.2nF	10nF	47nF	100nF	150nF
	3,000								
3026	4,000								
	3,000								
3838	4,000								
2020	5,000							-	+
3	7,000								

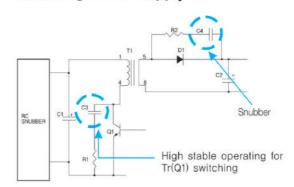
# **Application(Typical circuit)**

### DC-DC Converter

High stable operating for Tr(Q1) switching

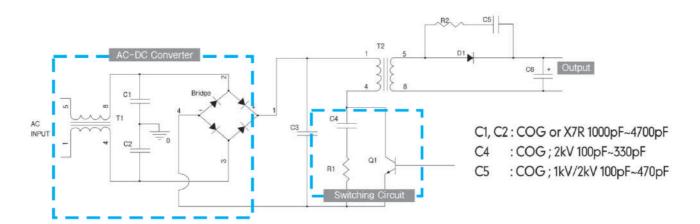
C2: X7R; 250V 10nF~47nF C3: COG; 630V 47pF~100pF

### Switching Power Supply

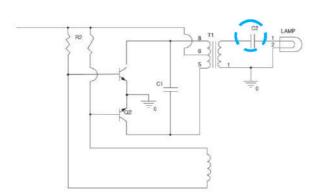


C3: COG, X7R; 2kV 100pF~1000pF C4: COG, X7R; 2kV 100pF~1000pF

### Primary circuit and Snubber switching power supply



### LCD back light Inverter



C2: COG; 3kV 10~100pF

# **SMD Type-High Voltage**

### **MLCC Applications for DC-DC Converter Modules**

High voltage MLCCs are mainly used to DC-DC converter modules for industrial applications which have high input voltage of typical 48V. These are used as functions of high frequency noise filtering(decoupling) of power line and snubber capacitor to protect switching device from unsafe transients by inductance of transformer or connection line due to switching operation.

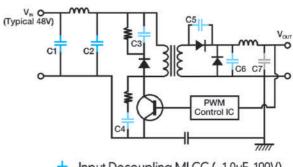
For these applications, MLCCs have merits for high allowable ripple current and high reliability.

Figure 2 shows isolated DC-DC converter circuit diagram and MLCC applications such as decoupling and snubber. Input voltage is 36~75V<sub>DC</sub>(typical 48V<sub>DC</sub>) for general industrial applications such as base station, server and network equipments. Decoupling MLCCs are applied to input and output(based on viewpoint of switch or transformer) power line to reduce ripple voltage, and MLCCs for snubber application used to absorb surge energy. SAMWHA MLCCs are recommended for each application as shown in Table 1.

Table 1. MLCC recommendation for isolated type DC-DC converter module

Items	MLCC Recommendation
*Input (C1, C2)	1210 X7R 470nF 100V 1812 X7R 1.0uF 100V
Snubber (C3~C6)	Available wide range of products 250V ~2kV (Available up to 7.2 kV) 100pF~2.2nF(Available up to 470nF)
Output (C7)	(High Capacitance Application) 1210 X5R 100uF 6.3V 1206 X5R 47uF 6.3V 0805 X5R 47uF 6.3V

<sup>\*</sup>Typical input voltage of 48V for industrial application



- Input Decoupling MLCC (~1.0uF 100V)
- Snubber Cap.(100pF~2.2nF 250V~2kV)
- Output Decoupling MLCC(10~100uF 6.3V

### **MLCC Applications for Ballast Circuits**

High voltage MLCCs are suitable for the ballast circuit as a function of resonant capacitor as presented in Figure 3. MLCCs with high voltage rating from 1kV to 3kV(available up to 7.2kV) are mainly used for these application. SAMWHA offers wide range of capacitance and rated voltage with high reliability.

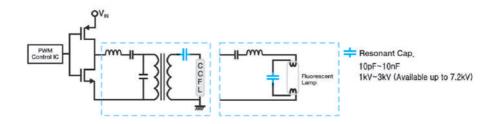


Fig. 3. Typical electronic ballast circuit and MLCC application

## **Caution(Rating)**

### 1. Operating Voltage

When DC-rated capacitors are to be used in AC or ripple current circuits, be sure to maintain the Vp-p Value of the applied voltage or the Vo-p which contains DC bias within the rated voltage range.

When the voltage is applied to the circuit, starting or stopping may generate irregular voltage for a transit period because of resonance or switching. Be sure to use a capacitor with a rated voltage range that includes these irregular voltages.

Voltage	DV Voltage	DC+AC Voltage	AC Voltage	Pulse Voltage(1)	Pulse Voltage(2)
Positional Measurement	V0-p	V0-p	Vp-p	Vp-p	Vp-p

#### 2. Test condition for AC withstanding Voltage

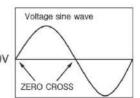
#### (1) Test Equipment

Tests for AC withstanding voltage should be made with equipment capable of creating a wave similar to a 50/60 Hz sine wave. If the distorted sine wave or overload exceeding the specified voltage value is applied, a defect may be caused.

#### (2) Voltage applied method

The capacitor's leads or terminals should be firmly connected to the output of the withstanding voltage test equipment, and then the voltage should be raised from near zero to the test voltage. If the test voltage is applied directly to the capacitor without raising it from near zero, it should be applied with the

\*zero cross. At the end of the test time, the test voltage should be reduced to near zero, and then the capacitor's leads or terminals should be taken off the output of the withstanding voltage test equipment. If the test voltage is applied directly to the OV capacitor without raising it from near zero, surge voltage may occur and cause a defect.



\*ZERO CROSS is the point where voltage sine wave

#### (3) Dielectric strength testing method

In case of dielectric strength test, the capacitor's is applied between the terminations for 1 to 5 sec., provided the charge/discharge current is less than 50mA.

### 3. Soldering

If a chip component is heated or cooled abruptly during soldering, it may crack due to the thermal shock. To prevent this, follow our recommendations below for adequate soldering conditions. Carefully perform preheating

so that temperature difference( $\Delta T$ ) between the solder and component surface is in the following range. The smaller the temperatures difference ( $\Delta T$ ) between the solder and component surface is, the smaller the influence on the chip is.

Chip Size Soldering Method	3.2×1.6mm and under	3.2×2.5mm and over
Reflow Method or Soldering Lron Method	∆ T≦ 190°C	⊿ T≦ 130°C

# **SMD Type-High Voltage**

SAMWHA CAPACITOR CO., LTD offers a line of MLCC(Multilayer Ceramic Capacitor). These parts are rated at 3kV dc and safety approved and certified to UL (Underwriters Laboratories Inc. ® )



OCD Home Quick Guide Contact Us UL.com

NWGQ8.E304146 Information Technology Equipment Including Electrical Business Equipment Certified for Canada - Component

Information Technology Equipment Including Electrical Business Equipment Certified for Canada - Component

See General Information for Information Technology Equipment Including Electrical Business Equipment Certified for Canada -

SAMWHA CAPACITOR CO LTD

E304146

124 BUK-RI NAMSA-MYEUN

YONGIN-SHI, KYONGGI-DO 449-880 REPUBLIC OF KOREA

Component Recognition, Model(s) CS45XXYYYTTTA302NRE.

Marking: Company name, model designation and Recognized Component Mark for Canada,

Last Updated on 2006-04-28

Questions?

Notice of Disclaimer

Page Top

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# **Reliability and Test Conditions**(General Type)

				Charac	teristi	c				Tes	st Method:	
No.	Ite	m	Temperature Compensating Type	Hi	igh Di	electri	c Cons	tant Ty	/ре		Condition	
1	Operating Temperatur	re Range	C0G: -55 to +125°C		-55 to -30 to		X5R:	:-55 to	+85℃			
2	Insulation Re	minutes of		More than 10,000 M $\Omega$ or 500 $\Omega$ F (Whichever is smaller)				/discharge current is				
3	Dielectric St	rength	No defects or abnormalities					- COG : The ra - X7R, X5R, Y - Applied be for 1 to 5 se - The charge less than 50	5V: * tween the conds. /discharge	×250% terminations		
4	Capacitance	e	Within the specified to	lerance	)) 9 0(					7725 01		
5	Dissipation	Dissipation Factor 30pF Min.: Q≥1,000(DF≤0.1%)				<b>25V</b> ≤3%/	<b>16V</b> ≤3.5%/	<b>10V</b> ≤5%/	<b>6.3V</b> ≤5%/	The capacita measured at and voltage	t 25℃ at the	e frequency
			30pF Max.: Q≥400+20C	X5R Y5V	*≤5% ≤5%/	*≤7% ≤7%/	*≤7% ≤9%	* ≤10% ≤12.5%/	*≤10% ≤15%	Cap.	Testing Frequency	Testing Voltage
		(DF≤1/(400+20C))			*≤9% ou can	(in the first	*≤12.5% the spe	*≤15% ecification		C0G (C≤1000pF)	1±0.1MHz	0.5 to 5Vrms
				the appendix for each product with mark						C0G (C >1000pF)	1±0.1kHz	1±0.2Vrms
										X7R, X5R, Y5V (C≤10μF)	1±0.1kHz	1±0.2Vrms
								X7R, X5R, Y5V (C >10µF)	120±24Hz	0.5±0.1Vrms		
6	Solderabilit Termination		Termination should be covered with more than 75% of new solder							- Pb-Free Typ Solder : 96.5 Solder Tem Immersion	5Sn-3Ag-0.5 perature : 2 Time : 3±0.	260±5℃
										at 80~120°C		ес
7	Resistance	Appearance	No marked defect							- Preheat the o		
	to Soldering Heat	Capacitchange	Within $\pm 2.5\%$ or $\pm 0.25$ pF (whichever is larger)						for 1 minute. (Preheating for 3225, 4520, 4532 Step1:100°C to 120°C, 1min Step2:170°C to 200°C, 1min) Immerse t			
Factor $Q \ge 1,000 (DF \le 0.1\%)$ $X7R \le 2.5\% / \le 3\% / \le 3.5\%$ $X5R \times 5\% \times 5\% \times 5\%$				16V ≤3.5%/ *≤7% ≤9% *≤12.5%	10V ≤5%/ *≤10% ≤12.5%/ *≤15%	6.3V ≤5%/ ∗≤10% ≤15%	capacitor in a eutectic solder solution - Soldering Temp. : 260±5°C - Immersion Time : 10±0.5sec - Initial measurement Perform the initial measurement accord to Note1 for Class    - Measurement after test Perform the final measurement accordi					
		I.R.	More than 10,000MΩ o	or 500Ω	F (Wh	icheve	er is sma	aller)		to Note2 for	Class   and	Class

# SMD Type

				Characteristic		Test	Meth	ods		
No.	lte	m	Temperature Compensating Type	High Dielectric Constant Type		and	Condit	ions		
8	Temperature Cycle	Appearance	No marking defects		Perform the five cycless according to the four heat treatments listed in the following table.					
		Capacitance Change	Within $\pm 2.5\%$ or $\pm 0.25 pF$ (whichever is larger)	X7R, X5R : Within ±7.5% Y5V : Within ±20%	Step	1	2	3	4	
		Dissipation Factor	30pF Min.: Q≥1,000 (DF≤0.1%)	Char. 50V Min. 25V 16V 10V 6.3V	Temp.	Min. Operating Temp.	Room Temp.	Max. Operating Temp.		
		(or Q)	30pF Max.: Q≥400+20C	X7R \( \le 5\% / \) \( \le 5\% / \) \( \le 5\% / \) \( \le 7.5\% /	Time (Min)	+0, -3 30±3	2 to 3	+3, -0 30±3	2 to 3	
			(DF≤1/(400+20C))	Y5V   \$\leq 10\%   \$\leq 12.5\%   \$\leq 12.5\%   \$\leq 12.5\%   \$\leq 12.5\%   \$\leq 20\%   \$\leq 20\%	Perfo acco - Mea Perfo	rding to surement orm the fir	itiall me Note1 fo after te al mea	easurement or Class    st surement nd Class	according	
		I.R.	More than 10,000MΩ o	r 500Q, F(Whichever is smaller)						
9	Humidity	Appearance	No marking defects		- Tem	perature	: 40±2	2℃		
	Load	Capacitance Change	Within ±7.5% or ±0.75pF (whichever is larger)	X7R, X5R : Within $\pm 12.5\%$ Y5V : Within $\pm 30\%$ , $-40\%$ (Y5V/1.0 $\mu$ F, 2.2 $\mu$ F, 4.7 $\mu$ F/10V) Within $\pm 30\%$ (others)	: Within +30%, -40% - Hour : 500±12hrs (Y5V/1.0µF, 2.2µF, 4.7µF/10V) - Test Voltage : The rated voltage					
		Dissipation Factor (or Q)	30 pF Min.: Q≥200 (DF≤0.5%) 30 pF Max.: Q≥100 +10/3C (DF≤1/(100+10/3C))	Char.     50V Min.     25V     16V     10V     6.3V       X7R     ≤5%/     ≤5%/     ≤7.5%/     ≤7.5%/     ≤7.5%/       X5R     *≤7.5%/     *≤10%/     *≤10%/     *≤12.5%/     *≤12.5%/       Y5V     ≤7.5%/     ≤10%/     *≤12.5%/     ≤15%/     *≤20%/       *≤12.5%/     *≤12.5%/     *≤15%/     *≤20%//	according to Note1 for Class    - Measurement after test Perform the final measurement ac to Note2 for Class   and Class					
		I.R.	More than 500MΩ or 2	5Ω.F(Whichever is smaller)						
10	High	Appearance	No marking defects		- Tes	ting time	: 1000 ±	12hrs		
	LUGU		Within $\pm 3\%$ or $\pm 0.3  \mathrm{pF}$ (whichever is larger)	X7R, X5R : Within $\pm 12.5\%$ Y5V : Within $\pm 30\%$ (Cap. < 1.0μF) Within +30%, -40% (Cap. $\geq 1.0$ μF)	<ul> <li>Applied voltage:         Rated voltage &lt; DC250V: ×200% </li> <li>Temperature:         COG, X7R → 125±3°C         X5R, Y5V → 85±3°C     </li> </ul>				<200%	
		Dissipation Factor (or Q)	$30  \mathrm{pF} \; \mathrm{Min.:}$ Q $\geq 350 \; \mathrm{(DF} \leq 0.3\%)$ $10  \mathrm{pF} \leq \mathrm{Cp} \leq 30  \mathrm{pF}:$ Q $\geq 275 + 5/2  \mathrm{C}$ (DF $\leq 1/(275 + 5/2  \mathrm{C})$ ) $10  \mathrm{pF} \; \mathrm{Max.:}$ Q $\geq 200 + 10  \mathrm{C}$ (DF $\leq 1/(200 + 10  \mathrm{C})$ )	Char.     50V Min.     25V     16V     10V     6.3V       X7R     ≤5%/ X5R     ≤5%/ *≤1.5%     ≤5%/ *≤10%     ≤7.5%/ *≤10%     ≤7.5%/ *≤12.5%     ≤7.5%/ *≤12.5%       Y5V     ≤7.5%/ *≤12.5%     ≤10%/ *≤12.5%     ≤15%/ *≤15%     ≤20%	- Initial Perfo acco - Mea Perfo	measure orm the in ording to I surement orm the fir	ment itial mea Note1 fo after te nal mea	asuremen or Class	according	
		I.R.	More than 1,000MΩ o	r 50Ω. F(Whichever & Smaller)						

				Characteristic	Test Methods		
No.	lte	m	Temperature Compensating Type	High Dielectric Constant Type	and Conditions		
11	Bending Strength		20mm	R340  Imm  45mm  or marking defects shall occur	- Substrate Material: Glass EPOXY Board - Board Thickness: 1.6mm 0.8mm(0603/1005size)  ** Test Condition - Bending Limit:1mm - Pressurizing Speed:1mm/sec - Holding Time: 5±1 sec		
		Capacitance Change	Within $\pm 5\%$ or $\pm 0.5  \mathrm{pF}$ (whichever is larger)	X7R, X5R : Within ±12.5% Y5V : Within ±30%			
12	Vibration	Appearance	No defects or abnorma	alities	* After soldering and then let sit for		
	Resistance	Capacitance	Whin the specified tole	erance	24hr+4hr (temperature compensating type), 24hr+4hr(high		
		Q/DF	30 <sub>p</sub> F Min.: Q 1,000 (DF 0.1%) 30 <sub>p</sub> F Max.: Q 400+20C (DF 1/ (400+20C))	Char.         50V Min.         25V         16V         10V         6.3V           X7R         ≤2.5%/         ≤3%/         ≤3.5%/         ≤5%/         ≤5%/         ≤5%/         ×≤10%         ×≤10%         ×≤10%           Y5V         ≤5%/         ≤7%/         ≤9%         ≤12.5%/         ×≤15%         ≤15%           ×≤9%         ×≤9%         ×≤12.5%/         ×≤15%         ≤15%	compensating type), 24hr+4hr(high dielectric constant type) at room temperature.  The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz, shall be traversed(from 10Hz to 55Hz then 10Hz again) in approximately 1 minute.  This motion shall be applied for a period of 2 hours in each 3mutually perpendicular directions(total is 6hours).		
13	Humidity	Appearance	No marking defects		- Temperature : 40±2°C		
	Steady State	Capacitance Change	Within ±5% or ±0.5pF (whichever is larger)	X7R, X5R : Within ±12.5% Y5V : Within ±30%	- Humidity : 90~95% - Hour : 500±12hours		
		Dissipation (or Q)	30pF Min.: Q≥350 (DF≤0.3%) 10pF≤Cp ≤ $30pF$ : Q≥275 +5/2C (DF≤ $1/(275+5/2C)$ ) 10pF Max.: Q≥200+10C (DF≤ $1/(200+10C)$ )	Char.         50V Min.         25V         16V         10V         6.3V           X7R         ≤5%/         ≤5%/         ≤5%/         ≤7.5%/         ≤7.5%/         ≤7.5%/         ≤2.5%/         ≤12.5%/         ≤12.5%/         ≤12.5%/         ≤20%           Y5V         ≤7.5%/ *≤12.5%         ≤10%/ *≤12.5%         ≤15%/ *≤15%/ *≤20%         ≤20%	Initial measurement     Perform the initial measurement according to Note1 for Class        Measurement after test     Perform the final measurement according to Note2 for Class    and Class		
		I.R		50Ω, F (Whichever is Smaller)			

# **SMD Type**

				Charact	teristic				Test Methods
No.	lte	m	Temperature Compensating Type	Hig	h Dielect	ric Constar	nt Type		and Conditions
14	Temperature	Capacitance Change		Char.	Temp. Range	Reference Temp.	Cap. Change	The t	erature Compensating Type: emperature coefficient is
	Characteristics			X7R	-55 to +125°C		Within ±15%	meas	mined using the capacitance ured in step 3 as a reference, n cycling the temperature
				X5R	+85°C	25℃	Within ±15%	seque	entially from step 1 through 5, +25 to 125°C) the capacitance
				Y5V	-30 to -85℃		Within 22% -82%	shall	be with in the specified ance for the temperature
								betwe values	dividing the difference een the maximum measured in the step 1, 3 and 5 by the value in step 3
		Temperature	Char. Temp. Temperature					Step	$\textbf{Temperature}(^{\circ}\!\mathbb{C})$
		Coefficient	Range Coefficient					1	25±2
			COG   -55 to   ±30ppm/°C					2	−55±3
			+123 C					3	25±2
								4	125±3(for C0G)
								5	25±2
								The ra chang value range	Dielectric Constant Type: anges of capacitance ge compared with the 25°C over the temperature shown in the table shall the specified range.
15	Preservatio	on(keeping)	* When solderability is recommended to be		Marie Carlotte Control			100000000000000000000000000000000000000	perature : 25°C ±10°C ive Humidity : Below 70% RH
16	The regula environme pollution m	ntal	※ Never use materials r Pb, Cd, Hg, Cr <sup>+6</sup> , PBB asbestos.						

- In case of high Voltage and thin layer type Capacitor, it can be different from nomal specification. So Please ask to our sales person.
- Note1. Initial Measurement for Class II Perform a heart tertment at 150+0, -10℃ for one hour and then let sit for 24±2 hours at room temperature, then measure
- Note2. Measurement after test
- 1. Class |

Let sit for  $24\pm2$  hours at room temperature, then measurement

Perform a heart treatment at 150±0, -10°C for one hour and then let sit for 24±2 hours at room temperature, then measure

# **SMD Type - High Frequency Capacitors**

SAMWHA high frequency MLCC(CF) products offers excellent performance in demanding high RF power applications requiring consistent and reliable operation.

The copper electrodes allow for Ultra -low ESR and high Q in the GHz frequencies.

The CF series products are your best choice for high RF power applications from UHF through microwave frequencies.

## **Applications**

- · RF Power Amplifiers, Low Noise Amplifiers
- Filter Networks
- Cable TV and telecommunication networks
- · GPS, Bluetooth and TV set-top boxes
- MRI Systems

### **Features**

- Ultra Low ESR
- High Q
- High Self Resonance
- · Capacitance Range: 0.5pF to 100pF
- Temperature characteristics: C0G

# **How to Order**(Product Identification)

CF 2012 COG 101 4 5 6

- 1 CF: High Frequency(SMD)
- Size Code

This is expressed in tens of a millimeter.

The first two digits are the length, The last two digits are width.

# **SMD Type - High Frequency Capacitors**

### Temperature Coefficient Code

Classification	Code	Temperature Range	Temperature Coefficient
Class	C0G	-55 to +125°C	±30 ppm/°C

### 4 Capacitance Code(Pico farads)

The nominal capacitance value in pF is expressed by three digit numbers.

The first two digits represents significant figures and the last digit denotes the number of zero

Ex.) 104 = 100000pF R denotes decimal 8R2 = 8.2pF

### 5 Capacitance Tolerance Code

Code	Tolerance	Code	Tolerance
В	±0.1pF	G	±2.0%
С	±0.25pF	J	±5%
D	±0.5pF	K	±10%
F	±1.0%	М	±20%

### 6 Voltage Code

Code	250	500	101	201	251
Rated	DC	DC	DC	DC	DC
Voltage	25V	50V	100V	200V	250V

### 7 Termination Code

N: Nickel-Tin Plate

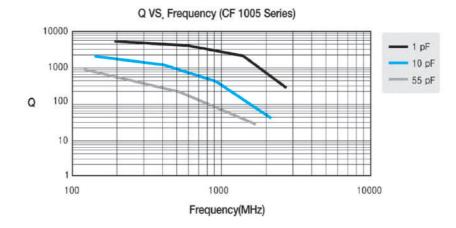
### 8 Packing Code

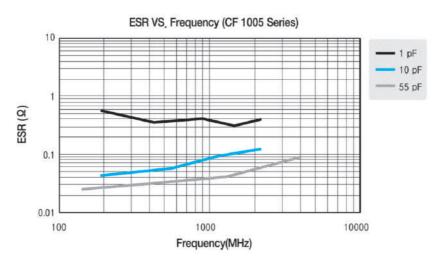
R: Reel Type, B: Bulk Type

### 9 Thickness Option

Size(mm) Thickne	Thickness(mm)		Carla	Si/\	Thickne	Code	
	1	Tol(±)	Code	Size(mm)	t	Tol(±)	Code
0603/1005	0.3	0.03	-	3216	1.15	0.15	E
1005	0.5	0.05	-	3216/3225	1.6	0.2	1
2012	0.6	0.1	А	3225	1.8	0.2	J
1608	0.8	0.1	В	3225/4532/5750	2	0.25	K
2012/3216	0.85	0.15	В	3225/4532/5750	2.5	0.25	L
2012	1.25	0.15	Е				

Size(mm)	Code	Packaging	Size(mm)	Code	Packaging
0603/1005	-	Paper Taping	3216	E	Embossed Taping
1005		Paper Taping	3216/3225	-1	Embossed Taping
2012	Α	Paper Taping	3225	J	Embossed Taping
1608	В	Paper Taping	3225/4532/5750	K	Embossed Taping
2012/3216	В	Paper Taping	3225/4532/5750	L	Embossed Taping
2012	Е	Embossed Taping			





# Appendix |

### COG-Temperature Compensating Type(0603~2012)

Туре			CI	)G			
Size(inch)	1005(	0402)	1608	(0603)	2012(0805)		
Volt(V) Cap.	25	50	50	100	50	100	
0.5pF(0R5)							
1 <sub>p</sub> F(010)							
2pF(020)							
3pF(030)							
4pF(040)							
5pF(050)							
6pF(060)							
7pF(070)							
8pF(080)							
9pF(090)							
10pF (100)							
12pF(120)							
15pF(150)							
18 <sub>p</sub> F(180)							
22pF(220)							
27 pF(270)							
33pF(330)							
39pF(390)							
47 pF (470)							
56pF(560)							
68pF(680)							
82pF(820)							
100pF(101)							

# **Automotive Applications**

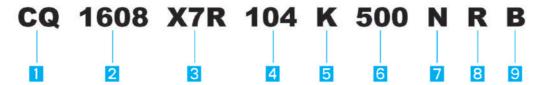
### **Features**

- SAMWHA Series meet AEC-Q200 requirements
- SAMWHA Series Certify IATF 16949(ISO/TS 16949), ISO 9001, ISO 14001
- SAMWHA Series are RoHS Compliant

## **Applications**

Automotive electronic equipment

### **How to Order**(Product Identification)



- 1 Monolithic Multilayer Ceramic Capacitor Leadless Type for Automotive Application
- 2 Size Code

This is expressed in tens of a millimeter.

The first two digits are the length, The last two digits are width.

### Temperature Coefficient Code

Classification	Code	Temperature Range	Capacitance Change or Temperature Coefficient
Class	C0G	-55 to +125°C	±30 ppm/℃
Class II	X7R	-55 to +125°C	±15%
Class II	X8R	-55 to +150°C	±15%

### 4 Capacitance Code(Pico farads)

The nominal capacitance value in pF is expressed by three digit numbers.

The first two digits represents significant figures and the last digit denotes the number of zero

Ex.) 104 = 100000pF

R denotes decimal

8R2 = 8.2pF

### 5 Capacitance Tolerance Code

Code	Tolerance	Code	Tolerance
В	±0.1pF	G	±2.0%
С	±0.25pF	3	<u>±</u> 5%
D	±0.5pF	K	$\pm 10\%$
F	±1.0%	М	$\pm 20\%$

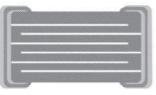
### 6 Voltage Code

Code	6R3	100	160	250	500	101	201	251	501	631	102	202	302
Rated	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC	DC
Voltage	6.3V	10V	16V	25V	50V	100V	200V	250V	500V	630V	1KV	2KV	3KV

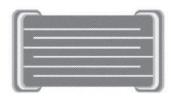
### Termination & Design Code

N: Nickel-Tin Plate A: Nickel-Tin Plate (Soft Termination) O: Open Mode F: Floating electrode

S: Ag/Ni-SN(Ag Epoxy/Nickel-Tin Plate)+Open mode type







Normal Type

Open Mode Type

Soft Termination Type

### 8 Packing Code

R: Reel Type, B: Bulk Type

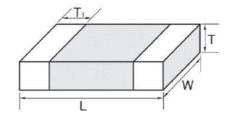
### Thickness Option

Si()	Thicknes	s(mm)	Code	Simplemen)	Thickne	ess(mm)	Code
Size(mm)	t	Tol(±)	Code	Size(mm)	1	Tol(±)	Code
0603/1005	0.3	0.03	(#6)	3216	1.15	0.15	Е
1005	0.5	0.05		3216/3225	1.6	0.2	- 1
2012	0.6	0.1	Α	3225	1.8	0.2	J
1608	0.8	0.1	В	3225/4532/5750	2	0.25	K
2012/3216	0.85	0.15	В	3225/4532/5750	2.5	0.25	L
2012	1.25	0.15	Е				

Size(mm)	Code	Packaging	Size(mm)	Code	Packaging
0603/1005	10=1	Paper Taping	3216	Е	Embossed Taping
1005		Paper Taping	3216/3225	- 1	Embossed Taping
2012	Α	Paper Taping	3225	J	Embossed Taping
1608	В	Paper Taping	3225/4532/5750	K	Embossed Taping
2012/3216	В	Paper Taping	3225/4532/5750	L	Embossed Taping
2012	Е	Embossed Taping			

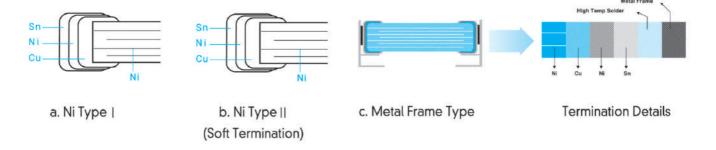
Temperature Characteristics See Page 39 (No.21)

# **Dimensions**



	Dimensions											
Code	Le	ngth	W	idth	T1(min)							
	L	Tol(±)	W	Tol(±)	()							
1005(0402)	1.00	0.05	0.50	0.05	0.05							
1608(0603)	1.60	0.15	0.80	0.10	0.10							
2012(0805)	2.00	0.20	1.25	0.15	0.10							
3216(1206)	3.20	0.30	1.60	0.20	0.15							
3225(1210)	3.20	0.40	2.50	0.25	0.15							

# **Construction of Termination**



dache 1p rere 1904.6.3 1:56 AM 페이지32 광진그래픽 CTP\_1500\_CMYK-POSI 2400DPI 175LPI T

# Capacitance Table.

### Class I (C0G)

Size Code (EIA Code)		1005(0402)				1608	(0603)			2012	(0805)			3216	(1206)		3225(1210)			
Rated Volt.(V)																				
Cap.	16	25	50	100	16	25	50	100	16	25	50	100	16	25	50	100	16	25	50	10
0.5pF(0R5)																				
1 <sub>p</sub> F(010)																				
2.2pF(2R2)																				
3pF(030)																				
4pF(040)								10.00												
4.7pF(4R7)											100									
5pF(050)																				
6.8pF(6R8)															1100					
7 <sub>p</sub> F(070)																				
8pF(080)																				
9pF(090)																				
10 <sub>p</sub> F(100)																				
12pF(120)																				
15 <sub>p</sub> F(150)																				П
18 <sub>p</sub> F(180)																				
22pF(220)																				
27 pF(270)																				
33 <sub>p</sub> F(330)																				
39pF(390)																				
47 pF (470)																				
56pF(560)																				
68pF(680)																				
82 pF (820)																				
100 <sub>p</sub> F(101)																				
120 <sub>p</sub> F(121)																				
150 <sub>p</sub> F(151)																				
180 <sub>p</sub> F(181)																				
220 <sub>p</sub> F(221)																				
270 <sub>p</sub> F(271)																				
330 <sub>p</sub> F(331)									-											
390 <sub>p</sub> F (391)																				
470 <sub>p</sub> F(471)																				
560 <sub>p</sub> F(561)																				
680 <sub>p</sub> F(681)																				
820 <sub>p</sub> F(821)																				
1000 <sub>p</sub> F(102)																				
1200pF(102)																				
1500pF (152)																				
1800 <sub>p</sub> F(182)																				
2200 <sub>p</sub> F(222)																				
3300 pF (332)																				$\vdash$
4700pF(472)																				

### Class II (X7R)

Size Code (EIA Code)		1005	(0402)			1608	(0603)			2012	(0805)		3216(1206)				3225(1210)			
Rated Volt.(V)	16	25	50	100	16	25	50	100	16	25	50	100	16	25	50	100	16	25	50	100
Cap.	10	25	50	100	10	23	30	100	10	25	50	100	10	25	30	100	10	25	50	100
1000pF(102)																				
1500 <sub>p</sub> F(152)																				
2200pF(222)																				
3300 <sub>p</sub> F(332)																				
4700pF(472)																				
6800pF(682)																				
10000 <sub>p</sub> F(103)																				
15000 <sub>p</sub> F(153)																				
22000 <sub>p</sub> F(223)																				
33000 <sub>p</sub> F(333)																				
47000pF(473)																				
68000 <sub>p</sub> F(683)																				
0.1uF(104)																				
0.15uF(154)																				
0.22uF(224)																				
0.33uF(334)																				
0.47uF(474)																				
0.68uF(684)																				
1.0uF(105)																				
2.2uF(225)																				
4.7uF(475)																				
10uF(106)																				
22uF(226)																				



Thin Layer Large-Capacitance Type for Automotive Application

# **Typical Performance Characteristics**

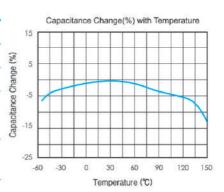
# X8R

### **Application**

The X8R series could be applicable to devices that operating in high-temperature environments Temperature Characteristics (x8r, -55 to 150°C, Capacitance Change  $\pm$ 15%) Excellent DC-bias, Temperature and Aging properties

### **Dielectric Characteristics**

±15%
-55~150°C
±10%, ±20%,
50V: 2.5% max. 25V: 3.0% max.
16V: 3.5% max. 10V: 5.0% max
More than 10,000MΩ or 50ΩF
(Whichever is smaller)
>2.5×RVDC
0.5 ~1.0Vrms
1±0.1kHz



Size Code (EIA Code)		1608	(0603)			2012	(0805)			3216	(1206)	
Rated Volt.(V)	16	25	50	100	16	25	50	100	16	25	50	100
Cap.	10	23	50	100	10	23	50	100	10	25	50	100
1000pF(102)												
4700pF(472)												
6800pF(682)												
10000pF(103)												
22000pF(223)												
470000pF(473)												
680000pF(683)												
0.1uF(104)												
0.15uF(154)												
0.22uF(224)												
0.47uF(474)												
0.68uF(684)	i.										10.0	
1.0uF(105)												
2.2uF(225)												
4.7uF(475)												
10uF(106)												
22uF(226)	i,											
47uF(226)												
100uF(226)												

# **Specifications and Test Methods**(For Automotive Applications)

NI -	AFC	0000	Specific	ation	Test Methods and Conditions						
No.	AEC-	·Q200	Class	Class	Test Methods and Conditions						
1.	Pre-and Post-S Electrical Test	itress									
2.	High	Appearance	No marking defects		Temperature : 150±3°C						
	Temperature Exposure	Capacitance Change	Within $\pm 2.5\%$ or $\pm 0.25$ pF (Whichever is larger)	Within±10.0%	Maintenance Time : $1000+48/-0$ hrs Let sit for $24\pm2$ hours at room temperature,						
	(Storage)	Q/D.F.	30pF Min.: Q≥1000 30pF Max.: Q≥400+20×C C: Nominal Capacitance(pF)	Rated Voltage 16V Min.: 0.05 Max. 10V: 0.075 Max.	then measure.						
		I.R.	More than $10,000M\Omega$ or $500$	P.F(Whichever is smaller)							
3.	Temperature	Appearance	No marking defects		Perform the 1000 cycles according to the four						
	Cycle	Capacitance Change	Within $\pm 2.5\%$ or $\pm 0.25$ pF (Whichever is larger)	Within±10.0%	heat treatments listed in the following table.  Let sit for 24±2 hours at room temperature, then measure.						
		Q/D.F.	30pF Min.: Q≥1000 30pF Max.: Q≥400+20×C C: Nominal Capacitance(pF)	Rated Voltage 16V Min.: 0.05 Max. 10V: 0.075 Max.	Step         1         2         3         4           Temp.(°C)         -55+0/-3         25±2         125+3/-0         25±2           Time(min)         15±3         1         15±3         1						
		I.R.	More than 10,000M $\Omega$ or 500 $\Omega$	2- F(Whichever is smaller)	Initial measurement Perform the initial measurement according to Note 1 for Class II.						
4.	Destructive Ph	ysical Analysis	No defects or abnormalities		Per EIA-469						
5.	Moisture Resistance	Appearance	No marking defects		Temperature : 25~65℃, Humidity : 80~98%						
		Capacitance Change	Within $\pm 3.0\%$ or $\pm 0.30$ pF (Whichever is larger)	Within±12.5%	Cycle Time: 24 hrs/cycle, 10 cycles  Humidity Humidity Humidity Humidity Humidity  90 88% 80 98% 80 98% 80 98%						
		Q/D.F.	30pF Min.: Q≥350 10pF Min. and 30pF Max.: Q≥275+5/2×C 10pF Max.: Q≥200+10×C C: Nominal Capacitance(pF)	Rated Voltage 16V Min.: 0.05 Max. 10V: 0.075 Max.	65 65 65 65 65 65 65 65 65 65 65 65 65 6						
		I.R.	More than 10,000MΩ or 500Ω	P.F(Whichever is smaller)	One cycle 24 hours 0 1 2 3 4 5 6 7 8 9 101 121 34 5 10 17 10 19 20 21 22 23 24 — Hours						
6.	Biased	Appearance	No marking defects		Temperature: 85±3°C						
	Humidity	Capacitance Change	Within $\pm 3.0\%$ or $\pm 0.30$ pF (Whichever is larger)	Within±12.5%	Humidity: 80~85% Applied Voltage: Rated Voltage and 1.3+0.2/-0V Maintenance Time: 1000+48/-0 hrs						
		Q/D.F.	30pF Min.: Q≥200 30pF Max.: Q≥100+10/3×C C: Nominal Capacitance(pF)	Rated Voltage 16V Min.: 0.05 Max. 10V: 0.075 Max.	Let sit for 24±2 hours at room temperature, then measure.  The charge/discharge current is less than						
		I.R.	More than 10,000MΩ or 500Ω	F(Whichever is smaller)	50mA.						
7.	Operational	Appearance	No marking defects		Temperature : 125±3°C						
	Life	Capacitance Change	Within $\pm 3.0\%$ or $\pm 0.30$ pF (Whichever is larger)	Within±12.5%	Applied Voltage : Rated Voltage × 200% Maintenance Time : 1000+48/-0 hrs						
		Q/D.F.	30pF Min.: Q≥350 10pF Min. and 30pF Max.: Q≥275+5/2×C 10pF Max.: Q≥200+10×C C: Nominal Capacitance(pF)	Rated Voltage 16V Min.: 0.05 Max. 10V: 0.075 Max.	Let sit for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA.  Initial Measurement for Class II  Applied 200% of the rated voltage for one hour at 125±3°C. Remove and let sit for 24±2 hours at						
		I.R.	More than 10,000Mℚ or 500ℚ	P·F(Whichever is smaller)							

		0000	Specific	ation	Test Methods and Conditions				
No.	AEC-	Q200	Class	Class	Test Methods and Conditions				
8.	External Visual	les .	No defects or abnormalities		Visual inspection				
9.	Physical Dimer	nsion	Within the specified dimension	ons	Using calipers				
10.	Resistance to	Appearance	No marking defects		Per MIL-STD-202 Method 215				
	Solvents	Capacitance Change	Within the specified tolerance	•					
		Q/D.F.	30pF Min.: Q≥1000 30pF Max.: Q≥400+20×C C: Nominal Capacitance(pF)	Rated Voltage 50V: 0.025 Max. 25V: 0.03 Max. 16V: 0.035 Max. 10V: 0.05 Max.					
		I.R.	More than 10,000M $\Omega$ or 500 $\Omega$	). F(Whichever is smaller)					
11.	Mechanical	Appearance	No marking defects		Three shocks in each direction should be				
	Shock	Capacitance Change	Within the specified tolerance	•	applied along 3 mutually perpendicular axes of the test specimen (18 shocks) Test Pulse				
		Q/D.F.	30pF Min.: Q≥1000 30pF Max.: Q≥400+20×C C: Nominal Capacitance(pF)	Rated Voltage 50V: 0.025 Max. 25V: 0.03 Max. 16V: 0.035 Max. 10V: 0.05 Max.	Wave form: Half-sine Duration: 0.5ms Peak value: 1,500G Velocity change: 4.7m/s				
		I.R.	More than 10,000M $\Omega$ or 500 $\Omega$	P: F(Whichever is smaller)					
12.	Vibration	Appearance	No defects or abnormalities		The specimens should be subjected to a				
		Capacitance Change	Within the specified tolerance	•	simple harmonic motion having a total amplitude of 1.5mm. The entire frequency range of 10 to 2,000 Hz and return to 10 Hz				
		Q/D.F.	30pF Min.: Q≥1000 30pF Max.: Q≥400+20×C C: Nominal Capacitance(pF)	Rated Voltage 50V: 0.025 Max. 25V: 0.03 Max. 16V: 0.035 Max. 10V: 0.05 Max.	should be traversed in 20 minutes. This cycle should be performed 12 times in each of three mutually perpendicular directions (total of 36 times).				
		I.R.	More than 10,000MΩ or 500Ω	. F(Whichever is smaller)					
13.	Resistance to	Appearance	No marking defects		Temperature(Eutectic solder solution) : 260±5℃				
	Soldering Heat	Capacitance Change	Within the specified tolerance	9	Dipping Time: 10±1s  Let sit for 24±2 hours at room temperature, then measure.				
		Q/D.F.	30pF Min.: Q≥1000 30pF Max.: Q≥400+20×C C: Nominal Capacitance(pF)	Rated Voltage 50V: 0.025 Max. 25V: 0.03 Max. 16V: 0.035 Max. 10V: 0.05 Max.	Initial measurement  Perform the initial measurement according to Note 1 for Class II.				
		I.R.	More than 10,000MΩ or 500Ω	2. F(Whichever is smaller)					

		0000	Specific	ation							
No.	AEC-	·Q200	Class	Class	Test	Methods a	ind Condi	tions			
14.	Thermal Shock	Appearance Capacitance Change Q/D.F.	No marking defects  Within $\pm 3.0\%$ or $\pm 0.30$ pF (Whichever is larger)  30pF Min.: $Q \ge 1000$	Within±12.5% Rated Voltage	heat treatme Transfer Time	Perform the 300 cycles according to the heat treatments listed in the following table. Transfer Time: 20s Max.  Let sit for 24±2 hours at room temperature, measure.					
			30pF Max.: Q≥400+20×C	50V: 0.025 Max.	Step	1		2			
			C: Nominal Capacitance(pF)	25V: 0.03 Max. 16V: 0.035 Max. 10V: 0.05 Max.	Temp.(°C Time(min		9, 170	125+3/-0 15±3			
		I.R.	More than 10,000MΩ or 500Ω	2-F(Whichever is smaller)	Initial measu Perform the Note 1 for Cl	initial meas	surement a	ccording to			
15.	ESD	Appearance	No marking defects		Per AEC-Q20	00-002					
		Capacitance Change	Within the specified tolerance	•							
		Q/D.F.	30pF Min.: Q≥1000 30pF Max.: Q≥400+20×C C: Nominal Capacitance(pF)	Rated Voltage 50V: 0.025 Max. 25V: 0.03 Max. 16V: 0.035 Max. 10V: 0.05 Max.							
		I.R.	More than 10,000MΩ or 500Ω	P: F(Whichever is smaller)							
16.	Solderability		95% of the terminations is to be and continuously.	pe soldered evenly	immerse the and rosin. Ir for 5+0/-0.5 s (b) Steam ag the capacito	(a) Preheat at 155℃ for 4 hours, and then immerse the capacitor in a solution of ethanol and rosin. Immerse in eutectic solder solution for 5+0/-0.5 seconds at 235±5℃.  (b) Steam aging for 8 hours, and then immerse the capacitor in a solution of ethanol and rosin. Immerse in eutectic solder solution for 5+0/-0.5					
					the capacito	ging for 8 ho or in a solution eutectic sol	on of ethan	nen immerse ol and rosin. on for 120±5			
17.	Electrical	Appearance	No defects or abnormalities		The capacita	ance/Q/D.F.	should be	measured at			
	Characteriza -tion	Capacitance Change	Within the specified tolerance	•	25°C at the fi table	requency ar	nd voltage s	shown in the			
		Q/D.F.	30pF Min.: Q≥1000 30pF Max.: Q≥400+20×C C: Nominal Capacitance(pF)	Rated Voltage 50V: 0.025 Max. 25V: 0.03 Max. 16V: 0.035 Max. 10V: 0.05 Max.	Class I C	C≤1000pF C>1000pF C>1000pF C≤110µF C>10µF	1±0.1MHz 1±0.1kHz 1±0.1kHz 1±0.1kHz 120±24Hz	Voltage 0.5~5Vrms 1±0.2Vrms 1±0.2Vrms 0.5±0.1Vrms			
		I.R. at 25°C	More than $100,000M\Omega$ or $1,000\Omega \cdot F$ (Whichever is smaller)	More than $100,000M\Omega$ or $500\Omega \cdot F$ (Whichever is smaller)	The state of the s	rated voltag		voltage not d 125°C for 2			
		I.R. at 125°C	More than $10,000M\Omega$ or $100\Omega \cdot F$ (Whichever is smaller)	More than 10,000MΩ or 10Ω·F (Whichever is smaller)							

				Specific	ation			
No.	AEC-	-Q200	Class	Class		Test Methods and Conditions		
17.		Dielectric Strength	No dielectric breakdown or me		echanical breakdown		Applied 250% of the rated voltage for 1~5 seconds The charge/discharge current is less than 50mA.	
18.	Board Flex	Appearance	No marking defect	ts			Apply a force in the direction shown in the	
Capacitance Change		Within ±5.0% or ±0.5pF (Whichever is larger)		Within±10.0%		following figure for 5±1 seconds.  Support  Solder Chip Printed circuit board before testing  45±2  Frobe to exert bending force Speed: 1.0mm/s  Printed circuit board under test  Displacement		
				for Class II: ≤2mm				
19.	Terminal	Appearance	No marking defect	ts			Apply *18N force in parallel with the test jig for	
	Strength	Capacitance Change	Within ±5.0% or ± (Whichever is large	53	Within±10.0%		60±1 seconds. *10N for 1608(EIA:0603) size 2N for 1005(EIA:0402) size	
20.	20. Beam Load Test		The chip endure fo			Apply a force as shown in the following figure.		
			Chip Length	Thicknot T≤0.		Force 8N	(i) Chip Length: 2.5mm Max.	
			2.5mm Max.	T>0.5		20N	Beam Speed: 0.5mm/s	
			3.2mm Min.	T<1.25 T≥:		15N 54.5N	Iron Board	
							(ii) Chip Length : 3.2mm Min.  Beam Speed : 2.5mm/s	

No.	AEC-Q200		Specifi	cation	T
NO.			Class	Test Methods and Conditions	
21.	Capacitance Capacitance Temperature Change			Within±15%	(i) Class I The temperature coefficient is determined
	Characteristics	Temperature Coefficient	0±30 ppm/°C		using the capacitance measured in step 3 as a reference. When cycling the temperature sequentially from step 1 through 5, the
		Capacitance Drift	Within $\pm 0.2\%$ or $\pm 0.05$ pF (Whichever is larger)		capacitance should be within the specified tolerance for the temperature coefficient.  The capacitance drift is calculated by dividing the differences
					between the maximum and minimum measured values in steps  1, 3 and 5 by the capacitance value in step 3.
					Step         1         2         3         4         5           Temp.(°c)         25±2         -55±3         25±2         125±3         25±2
					(ii) Class II  The ranges of capacitance change compared with the 25℃ value over the temperature range from -55℃ to 125℃
					Initial measurement  Perform the initial measurement according to  Note 1 for Class II.

\*Note 1. Initial Measurement for Class II

Perform a heat treatment at 150+0/-10  $^{\circ}\mathrm{C}$  for one hour, and then let sit for 24  $\pm$ 2 hours at room temperature, then measure.

# **Packing**

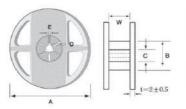
### **Bulk packing**

- 1000 pcs per Polybag
- ② 5 Polybags per Inner box
- 3 10 Inner boxes per Out box

# **Reel Packing**

- ① 8~10 Reels per Inner box
- 2 10 Inner boxes per Out box

### **Reel Dimensions**

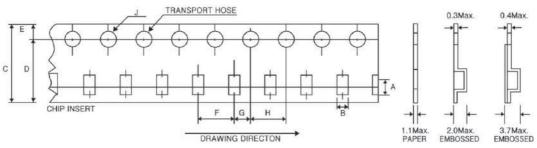


Mark	Size Code	EIA Code	Α	В	C	D	E	W
7" REEL	1005~3225	0402~1210	Ø178±2	Ø50Min.	Ø13±0.5	Ø21±0.8	$2\pm0.5$	10±1.5
13" REEL	1005~3225	0402~1210	Ø330±2	Ø70Min.	Ø13±0.5	Ø21±0.8	2±0.5	10±1.5

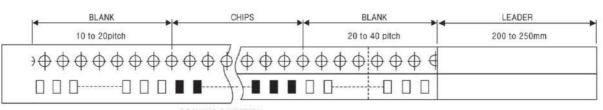
# **Number of Packages**

Туре	EIA CODE	7" Quantity(EA)/Reel	13" Quantity(EA)/Reel
1005	0402	10,000	50,000
1608	0603	4,000	16,000
2012	0805	3,000 ~ 4,000	10,000
3216	1206	2,000 ~ 4,000	6,000 ~ 10,000
3225	1210	1,000 ~ 3,000	4,000 ~ 10,000

# **Tape Dimensions**



TYPE	EIA CODE	Α	В	С	D	E	F	G	Н	J
1005	0402	1.15±0.1	$0.65 \pm 0.1$	$8.0 \pm 0.3$	$3.5 \pm 0.05$	1.75±0.1	2.0±0.05	$2.0 \pm 0.1$	$4.0 \pm 0.1$	1.5 ± 0.1
1608	0603	$1.9 \pm 0.2$	1.10±0.2	$8.0 \pm 0.3$	$3.5 \pm 0.05$	$1.75 \pm 0.1$	4.0±0.1	$2.0 \pm 0.1$	$4.0 \pm 0.1$	$1.5 \pm 0.1$
2012	0805	$2.4 \pm 0.2$	1.65 ± 0.2	$8.0 \pm 0.3$	$3.5 \pm 0.05$	$1.75 \pm 0.1$	4.0±0.1	$2.0 \pm 0.1$	$4.0 \pm 0.1$	1.5±0.1
3216	1206	$3.6 \pm 0.2$	2.00±0.2	$8.0 \pm 0.3$	$3.5 \pm 0.05$	1.75±0.1	4.0±0.1	$2.0 \pm 0.1$	4.0±0.1	1.5±0.1
3225	1210	$3.6 \pm 0.2$	$2.80 \pm 0.2$	$8.0 \pm 0.3$	$3.5 \pm 0.05$	1.75±0.1	4.0±0.1	$2.0 \pm 0.1$	4.0±0.1	1.5 ± 0.1



DRAWING DIRECTION

### Caution

#### ▶ Storage Condition

When solderability is considered, capacitor are recommended to be used in 12 months.

(1) Temperature:  $25\% \pm 10\%$ 

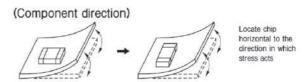
(2) Relative Humidity: Below 70% RH

### ▶ The Regulation of Environmental Pollution Materials

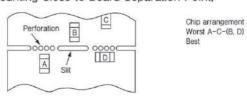
Never use materials mentioned below in MLCC products regulated this document. Pb, Cd, Hg, Cr+6, PBB(Polybrominated biphenyl), PBDE(Polybrominated diphenyl ethers), asbestos

### **▶** Mounting Position

Choose a mounting position that minimizes the stress imposed on the chip during flexing or bending of the board.



(Chip Mounting Close to Board Separation Point)



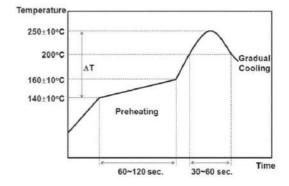
### ► Reflow Soldering

- 1. The sudden temperature change easily causes mechanical damages to ceramic components. Therefore, the preheating procedures should be required for the soldering of ceramic components.
- 2. Please refer to the recommended soldering profiles as shown in figures, and keep the temperature difference( $\triangle T$ ) within the range recommended in Table 1.

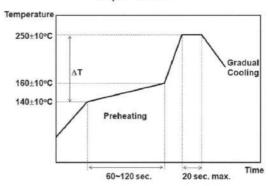
Table 1.

Size code (EIA Code)	Temperature Difference
1005~3216 (0402~1206)	∆T≤190°C
3225 (1210)	∆T≤130°C

#### Infrared Reflow



Vapor Reflow



(Typically represented by X7R temperature characteristic of which main composition is BaTiO3)

'Aging' / 'De-aging' Behavior of high dielectric MLCCs Please note that high dielectric type dielectric ceramic capacitors have a "normal" 'aging' behavior / characteristic, that is; their capacitance value decreases with time from its value when it was first manufactured. From that date, the capacitance value begins to decrease at a logarithmic rate defined by:

$$C_t = C_{48}(1 - k \log 10 t)$$

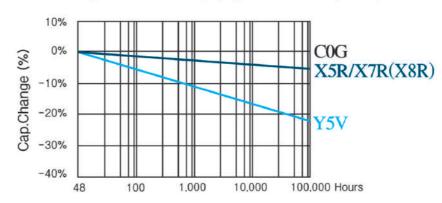
Ct: Capacitance value, t hours after the start of 'aging'

C<sub>48</sub>: Capacitance value, 48 hours after its manufacture

k: Aging constant (capacitance decrease per decade-hour)

t: time, in hours, from the start of 'aging'

### Ceramic's Capacitance Change(%) versus Time (hours)



The capacitance value can be restored(also known as 'de-aged') by exposing the component to elevated temperatures approaching its curie temperature(approximately 120°C). This 'de-aging' can occur during the component's solder-assembly onto the PCB, during life or temperature cycle testing, or by baking at 150℃ for about 1 hour.

Dielectric	Maximum percent capacitance loss per decade hour, k					
C0G	.0					
X7R	~3%					

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NMC0402NPO220J50TRPF NMC0402X5R105K6.3TRPF NMC0402X5R224K6.3TRPF NMC0402X7R103J25TRPF

NMC0402X7R153K16TRPF NMC0603NPO10IF50TRPF NMC0603NPO1R8C50TRPF NMC0603NPO201J50TRPF

NMC0603X5R475M6.3TRPF NMC0805NPO270J50TRPF NMC0805NPO681F50TRPF NMC0805NPO820J50TRPF

NMC0805X7R224K16TRPLPF NMC0805X7R224K25TRPF NMC1206X7R102K50TRPF NMC1206X7R475K10TRPLPF NMC-Q0402NPO8R2D200TRPF C1206C101J1GAC C1608C0G2A221J C1608X7R1E334K C2012C0G2A472J 2220J2K00562KXT

1812J2K00332KXT CDR04BX104AKSR CDR31BX103AKWR CDR33BX104AKUR CDR33BX683AKUS CGA2B2C0G1H010C

CGA2B2C0G1H040C CGA2B2C0G1H050C CGA2B2C0G1H060D CGA2B2C0G1H070D CGA2B2C0G1H120J CGA2B2C0G1H151J

CGA2B2C0G1H1R5C CGA2B2C0G1H2R2C CGA2B2C0G1H390J CGA2B2C0G1H391J CGA2B2C0G1H3R3C CGA2B2C0G1H680J

CGA2B2C0G1H6R8D CGA2B2C0G1H820J CGA2B2X8R1H152K CGA2B2X8R1H221K